

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Christophe MALEVILLE et al.

Confirmation No.

Application No.:

Group Art Unit:

Filing Date:

Examiner:

For: METHOD FOR RECYCLING A SUBSTRATE

Atty. Docket No.: 4717-5300

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed is a PTO form 1449 which lists (12) references for the Examiner's review and consideration. These references were cited in the European Search Reports and copies are enclosed herewith.

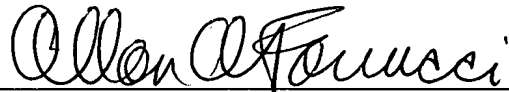
Pursuant to the recent rule change in the Official Gazette, copies of the U.S. references are not submitted. It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee or certification is believed to be due for this submission since the references are being submitted concurrent with the filing of this application. Should any fees be required, however, please charge such fees to **Winston & Strawn** Deposit Account No. 50-1814.

Date: _____

12/3/03

Respectfully submitted,



Allan A. Fanucci (Reg. No. 30,256)

WINSTON & STRAWN LLP
CUSTOMER NO. 28765
(212) 294-3311

Enclosures

LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				ATTY. DOCKET NO.:		APPLICATION NO.:	
				4717-5300			
				APPLICANT:			
				Christophe MALEVILLE et al.			
				FILING DATE:		GROUP:	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,994,207	11/1999	Henley et al.	438	515	
	AB	6,265,314 B1	7/2001	Black et al.	438	690	
	AC	6,284,628 B1	9/2001	Kuwahara et al.	438	459	
	AD	6,596,610 B1	7/2003	Kuwahara et al.	438	458	
	AE	2001/0055854 A1	12/2001	Nishida et al.	438	455	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	AF	EP 0 955 671 A1	11/1999	Europe			X
	AG	EP 1 156 531A1	11/2001	Europe			X
	AH	EP 1 170 801 A1	1/2002	Europe			X
	AI	WO 98/52216	11/1998	PCT			X
	AJ	WO 01/80308 A2	10/2001	PCT			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AK	XP000326239, "SURFACE PROFILOMETER WITH ULTRA-HIGH RESOLUTION" IBM Technical Disclosure Bulletin, IBM Corp, Vol. 35. No. 3 , pp. 207-208 (1992)					
	AL	M. Bruel, Auberton-Herve et al., "INDUSTRIAL STATUS OF SOI WAFER PRODUCTION AND NEW MATERIAL DEVELOPMENTS", Smart Technology, ECS Spring Meeting 99, Electronics Division, 9th Int'l Symposium on Insulator Technology.					
	AM						
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609 ; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							